## Features

- Low-voltage and Standard-voltage Operation – 1.8 (V<sub>cc</sub> = 1.8V to 5.5V)
- Internally Organized 256 x 8 (2K)
- Two-wire Serial Interface
- Schmitt Trigger, Filtered Inputs for Noise Suppression
- Bidirectional Data Transfer Protocol
- 1 MHz (5V), 400 kHz (1.8V, 2.5V, 2.7V) Compatibility
- Write Protect Pin for Hardware Data Protection
- 8-byte Page (2K) Write Modes
- Partial Page Writes Allowed
- Self-timed Write Cycle (5 ms max)
- High-reliability
  - Endurance: 1 Million Write Cycles
  - Data Retention: 100 Years
- 8-lead PDIP, 8-lead JEDEC SOIC, 8-lead Ultra-Thin Mini-MAP (MLP 2x3), 5-lead SOT23, 8-lead TSSOP and 8-ball dBGA2 Packages
- Lead-free/Halogen-free
- Available in Automotive
- Die Sales: Wafer Form, Waffle Pack and Bumped Wafers

## Description

The AT24C02B provides 2048 bits of serial electrically erasable and programmable read-only memory (EEPROM) organized as 256 words of 8 bits each. The device is optimized for use in many industrial and commercial applications where low-power and low-voltage operation are essential. The AT24C02B is available in space-saving 8-lead PDIP, 8-lead JEDEC SOIC, 8-lead Ultra-Thin Mini-MAP (MLP 2x3), 5-lead SOT23, 8-lead TSSOP, and 8-ball dBGA2 packages and is accessed via a Two-wire serial interface. In addition, the AT24C02B is available in 1.8V (1.8V to 5.5V) version.

Pin Name	Function	
A0 - A2	Address Inputs	
SDA	Serial Data	
SCL	SCL Serial Clock Input	
WP Write Protect		
NC	No Connect	
GND	Ground	
VCC	Power Supply	

8-lead Ultra-Thin Mini-MAP (MLP 2x3) VCC 8 1 A0 WP 7 2 A1 SCL 6 3 A2 SDA 5 4 GND Bottom View

8-lead TSSOP A0 1 8 VCC A1 2 7 WP A2 3 6 SCL GND 4 5 SDA

5-l€	ead SO	тс	23
SCL	1	5	□ WP
GND	2		
SDA	3	4	vcc

		dBG	A2
VCC WP SCL SDA	8	1	
WP	7	2	A1
SCL	6	3	A2
SDA	5	4	GND
Bo	otton	n Vie	ew
8-	lead	SO	IC
	4	0	

	11	0	
A1 🗔	2	7	🗀 WP
A2 🗔	3	6	SCL
GND 🗔	4	5	🗀 SDA

8-	le	ad PD	IP
A0 🗆	1	<b>U</b> 8	🗅 vcc
A1 🗆	2	7	U WP
A2 🗆	з	6	🗆 SCL
GND 🗆	4	5	🗆 SDA



Two-wire Serial EEPROM

2K (256 x 8)

# AT24C02B

5126F-SEEPR-2/07



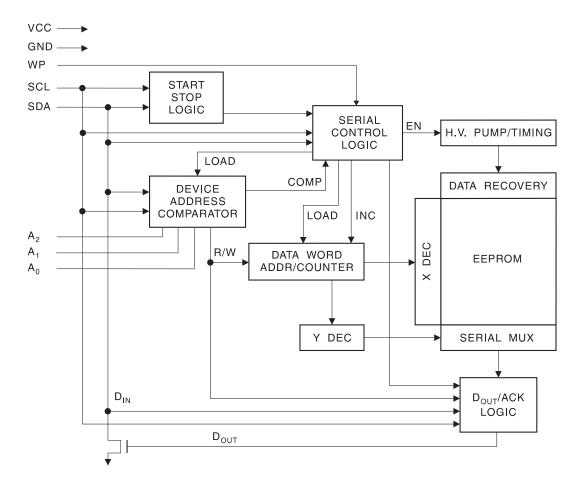


## **Absolute Maximum Ratings**

Operating Temperature55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground1.0V to +7.0V
Maximum Operating Voltage 6.25V
DC Output Current 5.0 mA

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### Figure 1. Block Diagram



# **Pin Description** SERIAL CLOCK (SCL): The SCL input is used to positive edge clock data into each EEPROM device and negative edge clock data out of each device.

**SERIAL DATA (SDA):** The SDA pin is bidirectional for serial data transfer. This pin is open-drain driven and may be wire-ORed with any number of other open-drain or open-collector devices.

**DEVICE/PAGE ADDRESSES (A2, A1, A0):** The A2, A1 and A0 pins are device address inputs that are hard wired for the AT24C02B. As many as eight 2K devices may be addressed on a single bus system (device addressing is discussed in detail under the Device Addressing section).

**WRITE PROTECT (WP):** The AT24C02B has a write protect pin that provides hardware data protection. The write protect pin allows normal read/write operations when connected to ground (GND). When the write protect pin is connected to  $V_{CC}$ , the write protection feature is enabled and operates as shown in Table 2.

	-		
Table	2.	Write	Protect

	Part of the Array Protected
WP Pin	
Status	24C02B
At V <sub>CC</sub>	Full (2K) Array
At GND	Normal Read/Write Operations

**Memory Organization** AT24C02B, 2K SERIAL EEPROM: Internally organized with 32 pages of 8 bytes each, the 2K requires an 8-bit data word address for random word addressing.





#### Table 3. Pin Capacitance<sup>(1)</sup>

Applicable over recommended operating range from  $T_A = 25^{\circ}C$ , f = 1.0 MHz,  $V_{CC} = +1.8V$ 

Symbol	Test Condition	Мах	Units	Conditions
C <sub>I/O</sub>	Input/Output Capacitance (SDA)	8	pF	V <sub>I/O</sub> = 0V
C <sub>IN</sub>	Input Capacitance (A <sub>0</sub> , A <sub>1</sub> , A <sub>2</sub> , SCL)	6	pF	$V_{IN} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

#### Table 4. DC Characteristics

Applicable over recommended operating range from:  $T_{AI} = -40^{\circ}C$  to +85°C,  $V_{CC} = +1.8V$  to +5.5V,  $V_{CC} = +1.8V$  to +5.5V (unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Units
V <sub>CC1</sub>	Supply Voltage		1.8		5.5	V
V <sub>CC2</sub>	Supply Voltage		2.5		5.5	V
V <sub>CC3</sub>	Supply Voltage		2.7		5.5	V
V <sub>CC4</sub>	Supply Voltage		4.5		5.5	V
I <sub>cc</sub>	Supply Current V <sub>CC</sub> = 5.0V	READ at 100 kHz		0.4	1.0	mA
I <sub>cc</sub>	Supply Current V <sub>CC</sub> = 5.0V	WRITE at 100 kHz		2.0	3.0	mA
I <sub>SB1</sub>	Standby Current V <sub>CC</sub> = 1.8V	$V_{IN} = V_{CC} \text{ or } V_{SS}$		0.6	3.0	μA
I <sub>SB2</sub>	Standby Current V <sub>CC</sub> = 2.5V	$V_{IN} = V_{CC} \text{ or } V_{SS}$		1.4	4.0	μA
I <sub>SB3</sub>	Standby Current V <sub>CC</sub> = 2.7V	$V_{IN} = V_{CC} \text{ or } V_{SS}$		1.6	4.0	μA
I <sub>SB4</sub>	Standby Current V <sub>CC</sub> = 5.0V	$V_{IN} = V_{CC} \text{ or } V_{SS}$		8.0	18.0	μA
ILI	Input Leakage Current	$V_{IN} = V_{CC} \text{ or } V_{SS}$		0.10	3.0	μA
I <sub>LO</sub>	Output Leakage Current	$V_{OUT} = V_{CC} \text{ or } V_{SS}$		0.05	3.0	μA
V <sub>IL</sub>	Input Low Level <sup>(1)</sup>		-0.6		V <sub>CC</sub> x 0.3	V
V <sub>IH</sub>	Input High Level <sup>(1)</sup>		V <sub>CC</sub> x 0.7		V <sub>CC</sub> + 0.5	V
V <sub>OL2</sub>	Output Low Level V <sub>CC</sub> = 3.0V	I <sub>OL</sub> = 2.1 mA			0.4	V
V <sub>OL1</sub>	Output Low Level V <sub>CC</sub> = 1.8V	I <sub>OL</sub> = 0.15 mA			0.2	V

Note: 1.  $V_{IL}$  min and  $V_{IH}$  max are reference only and are not tested.

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# AT24C02B

## Table 5. AC Characteristics

Applicable over recommended operating range from  $T_{AI} = -40^{\circ}C$  to  $+85^{\circ}C$ ,  $V_{CC} = +1.8V$  to +5.5V, CL = 1 TTL Gate and 100 pF (unless otherwise noted)

		1.8, 2	.5, 2.7	5.0-	volt	
Symbol	Parameter	Min	Max	Min	Мах	Units
f <sub>SCL</sub>	Clock Frequency, SCL		400		1000	kHz
t <sub>LOW</sub>	Clock Pulse Width Low	1.2		0.4		μs
t <sub>HIGH</sub>	Clock Pulse Width High	0.6		0.4		μs
t <sub>i</sub>	Noise Suppression Time		50		40	ns
t <sub>AA</sub>	Clock Low to Data Out Valid	0.1	0.9	0.05	0.55	μs
t <sub>BUF</sub>	Time the bus must be free before a new transmission can start	1.2		0.5		μs
t <sub>HD.STA</sub>	Start Hold Time	0.6		0.25		μs
t <sub>SU.STA</sub>	Start Setup Time	0.6		0.25		μs
t <sub>HD.DAT</sub>	Data In Hold Time	0		0		μs
t <sub>SU.DAT</sub>	Data In Setup Time	100		100		ns
t <sub>R</sub>	Inputs Rise Time <sup>(1)</sup>		0.3		0.3	μs
t <sub>F</sub>	Inputs Fall Time <sup>(1)</sup>		300		100	ns
t <sub>SU.STO</sub>	Stop Setup Time	0.6		.25		μs
t <sub>DH</sub>	Data Out Hold Time	50		50		ns
t <sub>wR</sub>	Write Cycle Time		5		5	ms
Endurance <sup>(1)</sup>	5.0V, 25°C, Byte Mode	1M				Write Cycles

Note: 1. This parameter is ensured by characterization only.





## **Device Operation**

**CLOCK and DATA TRANSITIONS:** The SDA pin is normally pulled high with an external device. Data on the SDA pin may change only during SCL low time periods (see Figure 4 on page 7). Data changes during SCL high periods will indicate a start or stop condition as defined below.

**START CONDITION:** A high-to-low transition of SDA with SCL high is a start condition which must precede any other command (see Figure 5 on page 8).

**STOP CONDITION:** A low-to-high transition of SDA with SCL high is a stop condition. After a read sequence, the stop command will place the EEPROM in a standby power mode (see Figure 5 on page 8).

**ACKNOWLEDGE:** All addresses and data words are serially transmitted to and from the EEPROM in 8-bit words. The EEPROM sends a zero to acknowledge that it has received each word. This happens during the ninth clock cycle.

**STANDBY MODE:** The AT24C02B features a low-power standby mode which is enabled: (a) upon power-up and (b) after the receipt of the STOP bit and the completion of any internal operations.

**MEMORY RESET:** After an interruption in protocol, power loss or system reset, any 2wire part can be reset by following these steps:

- 1. Clock up to 9 cycles.
- 2. Look for SDA high in each cycle while SCL is high.
- 3. Create a start condition.

## **Bus Timing**

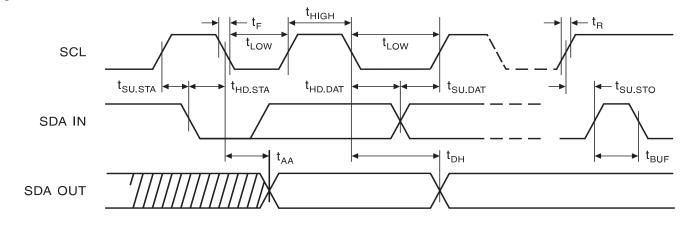
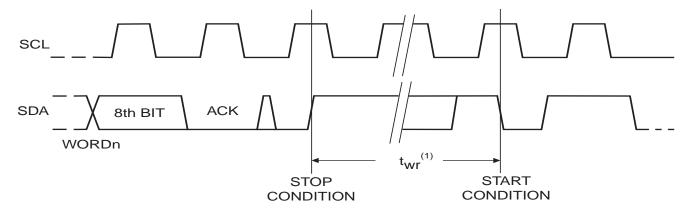


Figure 2. SCL: Serial Clock, SDA: Serial Data I/O®

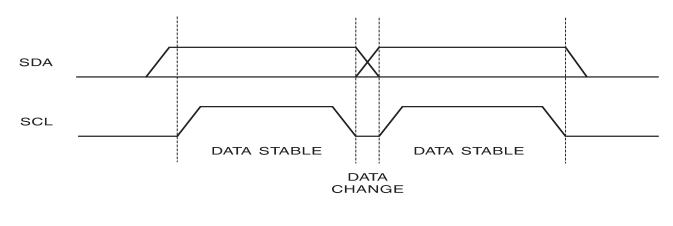
## Write Cycle Timing

Figure 3. SCL: Serial Clock, SDA: Serial Data I/O



Note: 1. The write cycle time  $t_{WR}$  is the time from a valid stop condition of a write sequence to the end of the internal clear/write cycle.

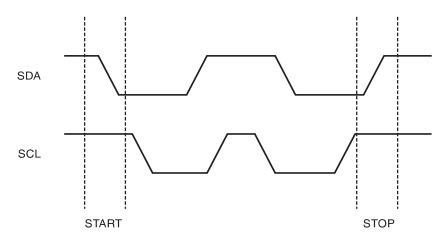
Figure 4. Data Validity



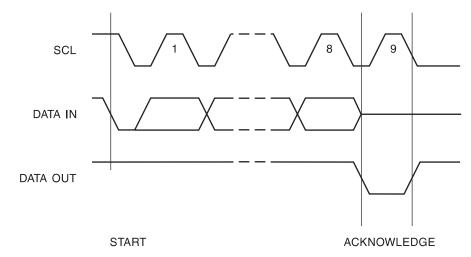




## Figure 5. Start and Stop Definition



## Figure 6. Output Acknowledge



8

## **Device Addressing**

The 2K EEPROM device requires an 8-bit device address word following a start condition to enable the chip for a read or write operation (refer to Figure 7).

The device address word consists of a mandatory one, zero sequence for the first four most significant bits as shown. This is common to all the EEPROM devices.

The next 3 bits are the A2, A1 and A0 device address bits for the 2K EEPROM. These 3 bits must compare to their corresponding hard-wired input pins.

The eighth bit of the device address is the read/write operation select bit. A read operation is initiated if this bit is high and a write operation is initiated if this bit is low.

Upon a compare of the device address, the EEPROM will output a zero. If a compare is not made, the chip will return to a standby state.

**Write Operations BYTE WRITE:** A write operation requires an 8-bit data word address following the device address word and acknowledgment. Upon receipt of this address, the EEPROM will again respond with a zero and then clock in the first 8-bit data word. Following receipt of the 8-bit data word, the EEPROM will output a zero and the addressing device, such as a microcontroller, must terminate the write sequence with a stop condition. At this time the EEPROM enters an internally timed write cycle, t<sub>WR</sub>, to the nonvolatile memory. All inputs are disabled during this write cycle and the EEPROM will not respond until the write is complete (see Figure 8 on page 11).

**PAGE WRITE:** The 2K EEPROM is capable of an 8-byte page write.

A page write is initiated the same as a byte write, but the microcontroller does not send a stop condition after the first data word is clocked in. Instead, after the EEPROM acknowledges receipt of the first data word, the microcontroller can transmit up to seven data words. The EEPROM will respond with a zero after each data word received. The microcontroller must terminate the page write sequence with a stop condition (see Figure 9 on page 11).

The data word address lower three bits are internally incremented following the receipt of each data word. The higher data word address bits are not incremented, retaining the memory page row location. When the word address, internally generated, reaches the page boundary, the following byte is placed at the beginning of the same page. If more than eight data words are transmitted to the EEPROM, the data word address will "roll over" and previous data will be overwritten.

**ACKNOWLEDGE POLLING:** Once the internally timed write cycle has started and the EEPROM inputs are disabled, acknowledge polling can be initiated. This involves sending a start condition followed by the device address word. The read/write bit is representative of the operation desired. Only if the internal write cycle has completed will the EEPROM respond with a zero allowing the read or write sequence to continue.

# **Read Operations** Read operations are initiated the same way as write operations with the exception that the read/write select bit in the device address word is set to one. There are three read operations: current address read, random address read and sequential read.

**CURRENT ADDRESS READ:** The internal data word address counter maintains the last address accessed during the last read or write operation, incremented by one. This address stays valid between operations as long as the chip power is maintained. The address "roll over" during read is from the last byte of the last memory page to the first





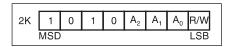
byte of the first page. The address "roll over" during write is from the last byte of the current page to the first byte of the same page.

Once the device address with the read/write select bit set to one is clocked in and acknowledged by the EEPROM, the current address data word is serially clocked out. The microcontroller does not respond with an input zero but does generate a following stop condition (see Figure 10 on page 11).

**RANDOM READ:** A random read requires a "dummy" byte write sequence to load in the data word address. Once the device address word and data word address are clocked in and acknowledged by the EEPROM, the microcontroller must generate another start condition. The microcontroller now initiates a current address read by sending a device address with the read/write select bit high. The EEPROM acknowledges the device address and serially clocks out the data word. The microcontroller does not respond with a zero but does generate a following stop condition (see Figure 11 on page 12).

**SEQUENTIAL READ:** Sequential reads are initiated by either a current address read or a random address read. After the microcontroller receives a data word, it responds with an acknowledge. As long as the EEPROM receives an acknowledge, it will continue to increment the data word address and serially clock out sequential data words. When the memory address limit is reached, the data word address will "roll over" and the sequential read will continue. The sequential read operation is terminated when the microcontroller does not respond with a zero but does generate a following stop condition (see Figure 12 on page 12).

## Figure 7. Device Address



#### Figure 8. Byte Write

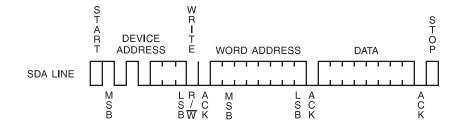


Figure 9. Page Write

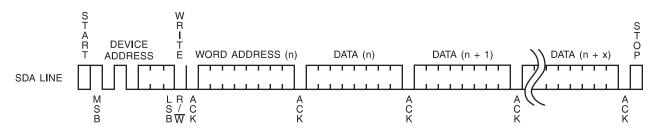
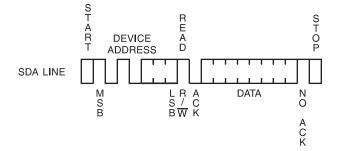


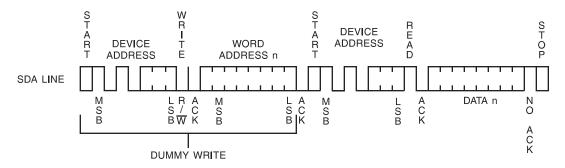
Figure 10. Current Address Read



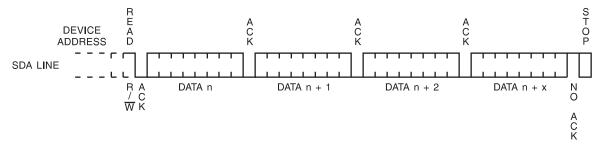




#### Figure 11. Random Read



## Figure 12. Sequential Read



## AT24C02B Ordering Information

Ordering Code	Voltage	Package	Operation Range	
AT24C02B-PU (Bulk form only)	1.8	8P3		
AT24C02BN-SH-B <sup>(1)</sup> (NiPdAu Lead Finish)	1.8	8S1		
AT24C02BN-SH-T <sup>(2)</sup> (NiPdAu Lead Finish)	1.8	8S1	Lead-free/Halogen-free/ Industrial Temperature (–40°C to 85°C)	
AT24C02B-TH-B <sup>(1)</sup> (NiPdAu Lead Finish)	1.8	8A2		
AT24C02B-TH-T <sup>(2)</sup> (NiPdAu Lead Finish)	1.8	8A2		
AT24C02BY6-YH-T <sup>(2)</sup> (NiPdAu Lead Finish)	1.8	8Y6		
AT24C02B-TSU-T <sup>(2)</sup>	1.8	5TS1		
AT24C02BU3-UU-T <sup>(2)</sup> (NiPdAu Lead Finish)	1.8	8U3-1		
AT24C02B-W-11 <sup>(3)</sup>	1.8	Dia Cala	Industrial Temperature	
		Die Sale	(–40°C to 85°C)	

Notes: 1. "B" denotes bulk.

2. "-T" denotes tape and reel. SOIC = 4K per reel. TSSOP, Ultra Thin Mini-MAP, SOT23, and dBGA2 = 5K per reel.

3. Available in waffle pack, tape and reel, and wafer form; order as SL788 for inkless wafer form. Bumped die available upon request. Please contact Serial Interface Marketing.

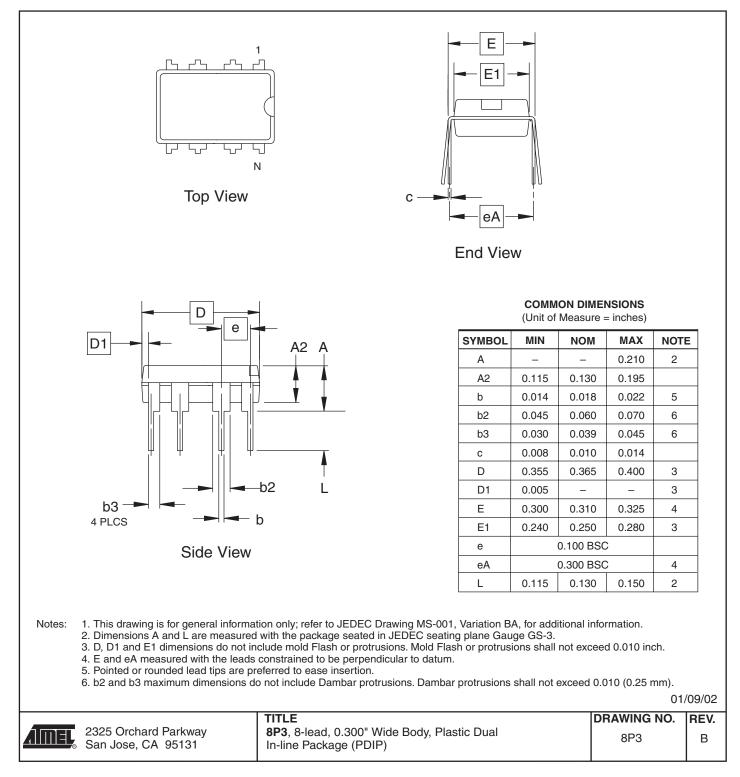
Package Type			
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)		
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)		
8A2	8-lead, 4.4 mm Body, Plastic Thin Shrink Small Outline Package (TSSOP)		
8Y6	8-lead, 2.0 mm x 3.00 mm Body, 0.50 mm Pitch, Ultra Thin Mini-MAP, Dual No Lead Package (DFN), (MLP 2x3 mm)		
5TS1	5-lead, 2.90 mm x 1.60 mm Body, Plastic Thin Shrink Small Outline Package (SOT23)		
8U3-1	8-ball, die Ball Grid Away Package (dBGA2)		
Options			
-1.8	Low-voltage (1.8V to 5.5V)		





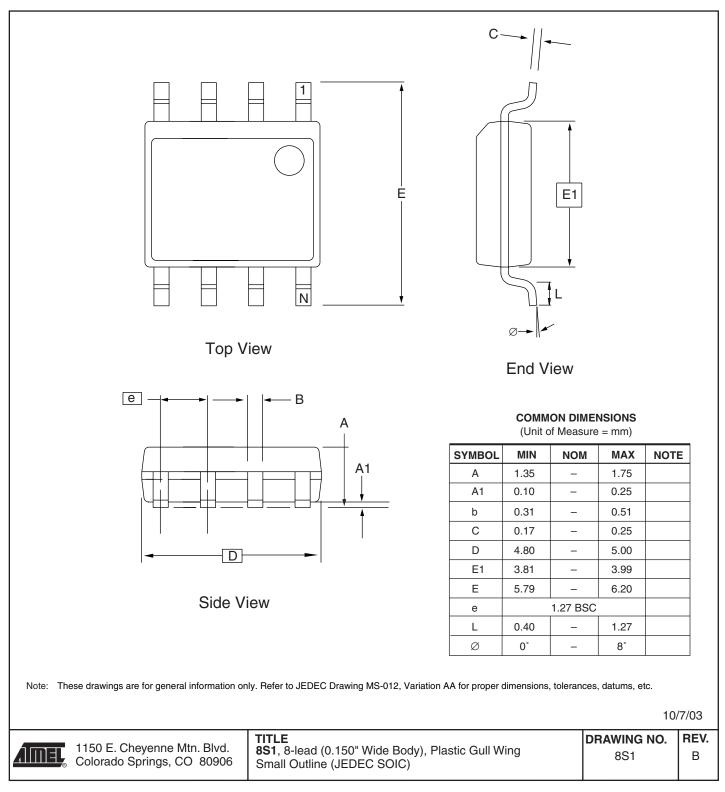
## **Packaging Information**

## 8P3 – PDIP



# AT24C02B

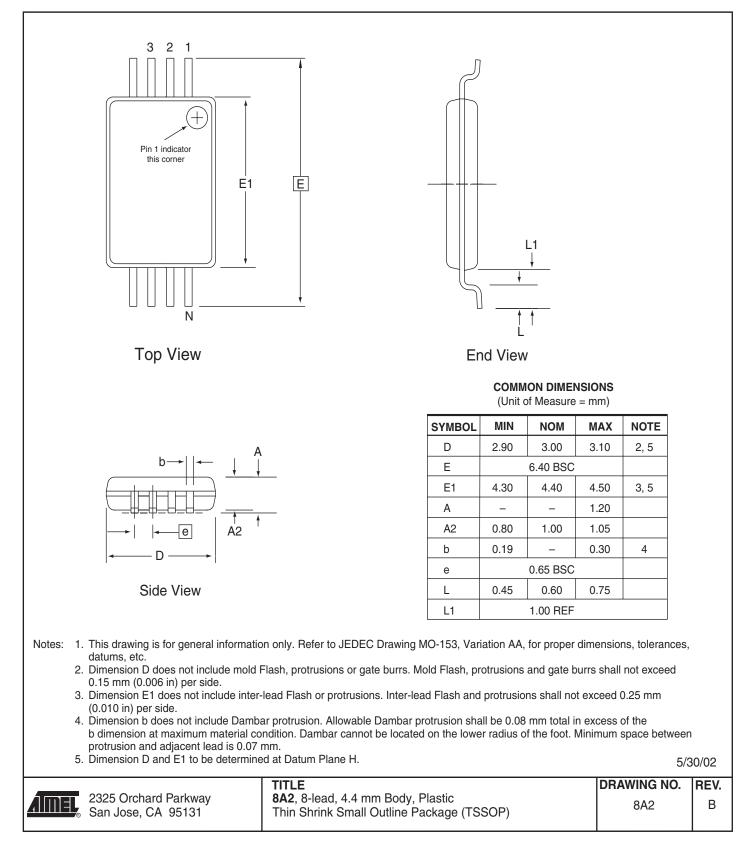
## 8S1 – JEDEC SOIC





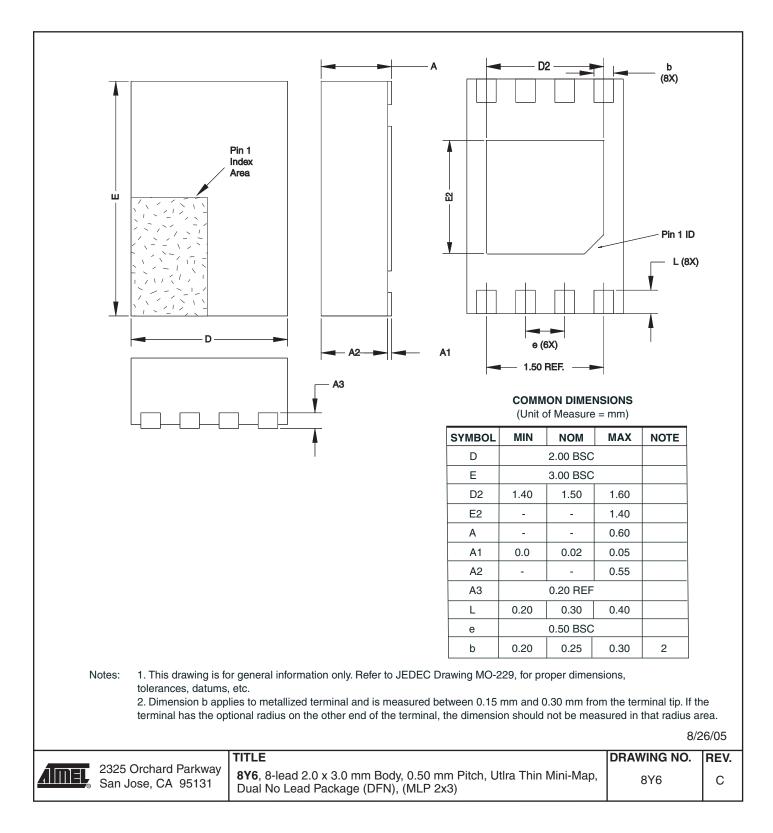


## 8A2 – TSSOP



16 **AT24C02B** 

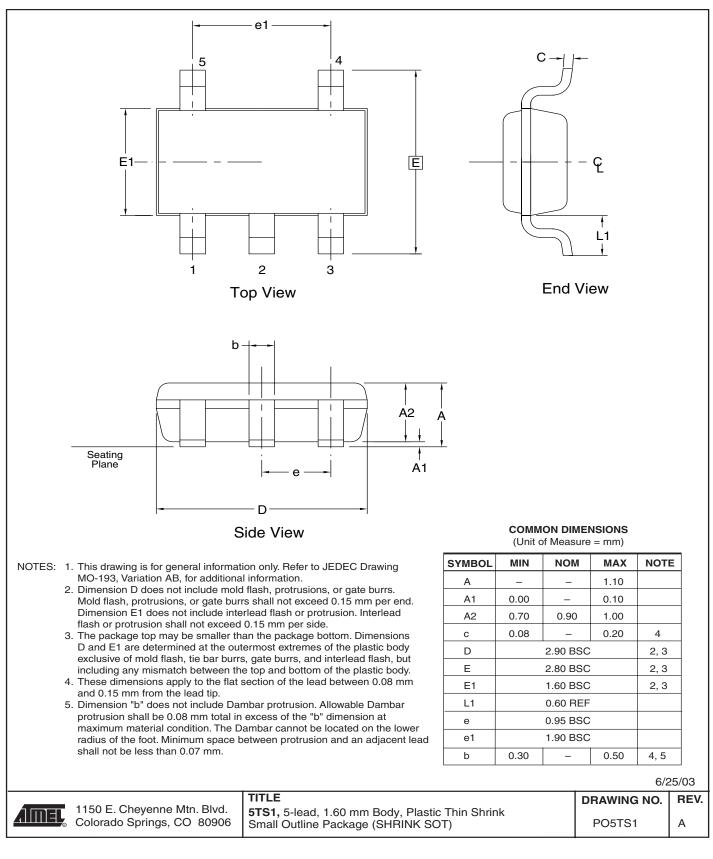
## 8Y6 - Mini Map





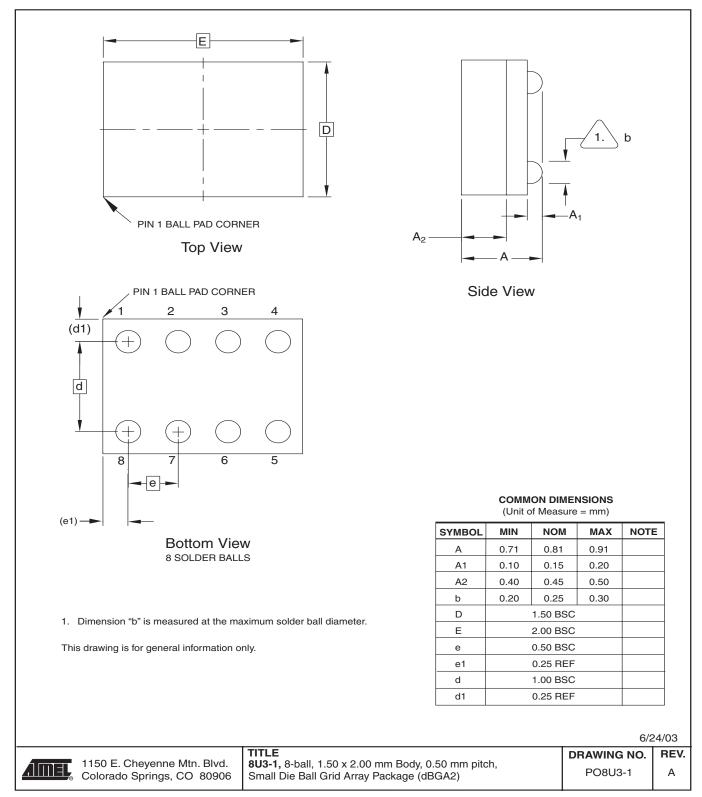


## 5TS1 - SOT23



AT24C02B

## 8U3-1 – dBGA2







## **Revision History**

Doc. Rev.	Date	Comments
5126F	2/2007	Corrected dBGA2 package code on Pg 13 Removed 'Preliminary'
5126E	2/2007	Added Ultra-Thin on Pg 1 Replaced Fig 6 with the correct figure
5126D	7/2006	Implemented Revision History Added Preliminary status; Added 'Available in Automotive' to Features



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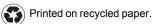
#### Biometrics/Imaging/Hi-Rel MPU/

High Speed Converters/RF Datacom Avenue de Rochepleine BP 123 38521 Saint-Egreve Cedex, France Tel: (33) 4-76-58-30-00 Fax: (33) 4-76-58-34-80

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